TOSHIBA Field-Effect Transistor Silicon N-Channel MOS Type

# SSM3K36MFV

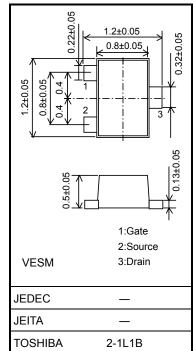
○ High-Speed Switching Applications

- 1.5-V drive
- Low ON-resistance:  $R_{on}$  = 1.52  $\Omega$  (max) (@V<sub>GS</sub> = 1.5V)
  - : R<sub>on</sub> = 1.14 Ω (max) (@V<sub>GS</sub> = 1.8V)
    - :  $R_{on} = 0.85 \Omega (max) (@V_{GS} = 2.5V)$
    - :  $R_{on} = 0.66 \Omega (max) (@V_{GS} = 4.5V)$
    - : R<sub>on</sub> = 0.63 Ω (max) (@V<sub>GS</sub> = 5.0V)

#### Absolute Maximum Ratings (Ta = 25°C)

Characteristic		Symbol	Rating	Unit	
Drain-source voltage		V <sub>DSS</sub>	20	V	
Gate-source voltage		V <sub>GSS</sub>	± 10	V	
Drain current	DC	ID	500	mA	
	Pulse	I <sub>DP</sub>	1000		
Drain power dissipation		P <sub>D</sub> (Note 1)	150	mW	
Channel temperature		T <sub>ch</sub>	150	°C	
Storage temperature		T <sub>stg</sub>	–55 to 150	°C	

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.



Weight: 1.5 mg (typ.)

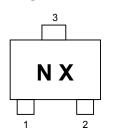
Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

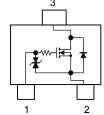
Note1:Mounted on an FR4 board

(25.4 mm  $\times$  25.4 mm  $\times$  1.6 mm, Cu Pad: 0.585 mm<sup>2</sup>)

#### Marking

#### Equivalent Circuit (top view)





Unit: mm

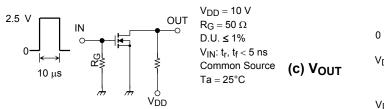
### Electrical Characteristics (Ta = 25°C)

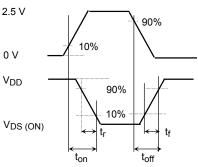
Char	Characteristics Symbol Test Conditions		Test Conditions	Min	Тур.	Max	Unit
Drain agurag brookdown voltago	V (BR) DSS	$I_D = 1 \text{ mA}, V_{GS} = 0$	20	_		v	
Drain-source breakdown voltage		V (BR) DSX	$I_D = 1 \text{ mA}, V_{GS} = -10 \text{ V}$	GS = - 10 V 12 -		_	- V
Drain cutoff current		I <sub>DSS</sub>	$V_{DS} = 20 V, V_{GS} = 0$	_		1	μA
Gate leakage current		IGSS	$V_{GS}=\pm 10~V,~V_{DS}=0$	_		±1	μA
Gate threshold voltage		V <sub>th</sub>	$V_{DS} = 3 V, I_D = 1 mA$	0.35		1.0	V
Forward transfer a	admittance	Y <sub>fs</sub>	$V_{DS} = 3 V, I_D = 200 mA$ (Note2)	420	840	_	mS
		$I_D = 200 \text{ mA}, V_{GS} = 5.0 \text{ V}$ (Note2)	_	0.46	0.63	Ω	
			$I_D = 200 \text{ mA}, V_{GS} = 4.5 \text{ V}$ (Note2)	_	0.51		0.66
Drain-source ON-resistance	R <sub>DS (ON)</sub>	$I_D = 200 \text{ mA}, V_{GS} = 2.5 \text{ V}$ (Note2)	—	0.66	0.85		
			$I_D = 100 \text{ mA}, V_{GS} = 1.8 \text{ V} (Note2)$	_	0.81		1.14
			$I_D = 50 \text{ mA}, V_{GS} = 1.5 \text{ V}$ (Note2)	_	0.95		1.52
Input capacitance		C <sub>iss</sub>	$V_{DS} = 10 \text{ V}, \text{ V}_{GS} = 0, \text{ f} = 1 \text{ MHz}$	_	46		pF
Output capacitance		C <sub>oss</sub>		_	10.8	—	
Reverse transfer capacitance		C <sub>rss</sub>		_	7.3		
Total Gate Charge		Qg	V <sub>DS</sub> = 10V, I <sub>D</sub> = 0.5 A V <sub>GS</sub> = 4.0 V	_	1.23	—	nC
Gate-Source Charge		Q <sub>gs</sub>		_	0.60		
Gate-Drain Charge		Q <sub>gd</sub>	V GS = 4.0 V	—	0.63	_	
Switching time	Turn-on time	t <sub>on</sub>	$V_{DD} = 10 \text{ V}, \text{ I}_{D} = 200 \text{ mA}$	_	30	_	- ns
	Turn-off time	t <sub>off</sub>	$V_{GS}$ = 0 to 2.5 V, $R_G$ = 50 $\Omega$	_	75	_	
Drain-source forward voltage VDSF		VDSF	$I_D = -0.5 \text{ A}, V_{GS} = 0 \text{ V}$ (Note2)	_	-0.88	-1.2	V

Note2: Pulse test

### **Switching Time Test Circuit**

#### (a) Test Circuit





#### **Usage Considerations**

Let V<sub>th</sub> be the voltage applied between gate and source that causes the drain current (I<sub>D</sub>) to below (1 mA for the SSM3K36MFV). Then, for normal switching operation, V<sub>GS(on)</sub> must be higher than V<sub>th</sub>, and V<sub>GS(off)</sub> must be lower than V<sub>th</sub>. This relationship can be expressed as: V<sub>GS(off)</sub> < V<sub>th</sub> < V<sub>GS(on)</sub>.

(b) V<sub>IN</sub>

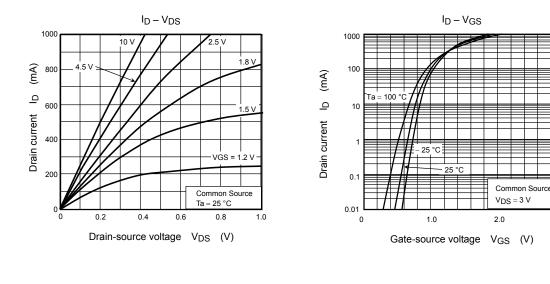
Take this into consideration when using the device.

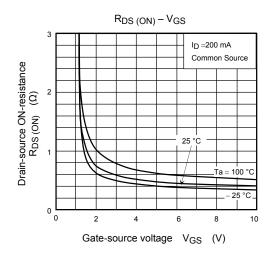
#### **Handling Precaution**

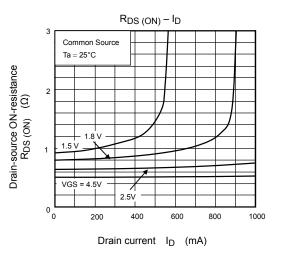
When handling individual devices that are not yet mounted on a circuit board, make sure that the environment is protected against electrostatic discharge. Operators should wear antistatic clothing, and containers and other objects that come into direct contact with devices should be made of antistatic materials.

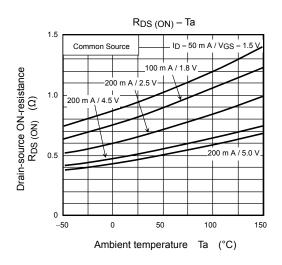
# TOSHIBA

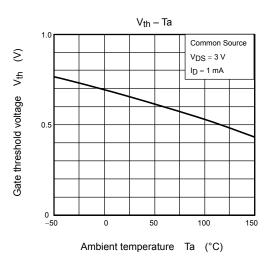
3.0











## TOSHIBA

Common Source

š

-1.5

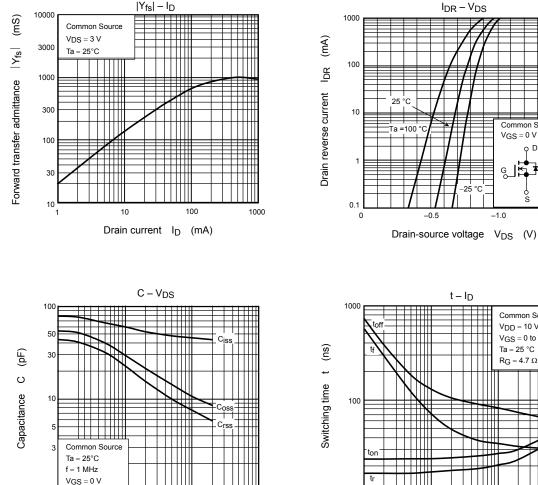
D **∃**† I<sub>DR</sub>

VGS = 0 V

G

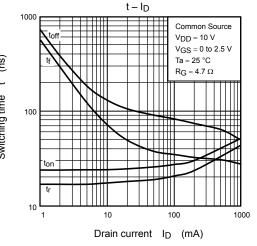
-1.0

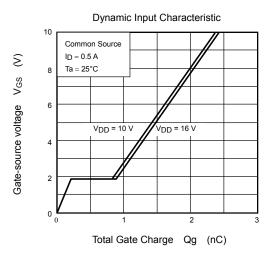
-25



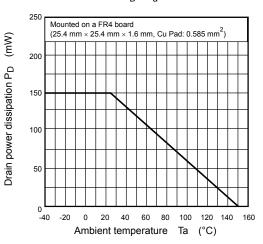
100

10 1 Drain-source voltage VDS (V)





P<sub>D</sub> – T<sub>a</sub>



1 0.1

#### **RESTRICTIONS ON PRODUCT USE**

20070701-EN GENERAL

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  stress. It is the responsibility of the buyer, when utilizing TOSHIBA products, to comply with the standards of
  safety in making a safe design for the entire system, and to avoid situations in which a malfunction or failure of
  such TOSHIBA products could cause loss of human life, bodily injury or damage to property.

In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent TOSHIBA products specifications. Also, please keep in mind the precautions and conditions set forth in the "Handling Guide for Semiconductor Devices," or "TOSHIBA Semiconductor Reliability Handbook" etc.

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